IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Abhijt Jas et al.

Title: LINEAR FEEDBACK SHIFT REGISTER RESEEDING

Docket No.:   884.911US1   Serial No.: 10/666169
Filed: September 19, 2003   Due Date: N/A
Examiner: Unknown   Group Art Unit: 2816

· Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

We are transmitting herewith the following attached items (as indicated with an "X"):

X   A return postcard.

X   A Supplemental Information Disclosure Statement (1 pgs.), Form 1449 (1 pg.), and copies of 16 cited documents.

If not provided for in a separate paper filed herewith, Please consider this a PETITION FOR EXTENSION OF TIME for sufficient number of months to enter these papers and please charge any additional fees or credit overpayment to Deposit Account No. 19-0743.

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.   By: _____
Customer Number 21186   Atty. David R. Cochran
Reg. No. 46,632
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CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 22day of March, 2004.

Chris Hammond   Chs Hammond
Name   Signature

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.
(GENERAL)
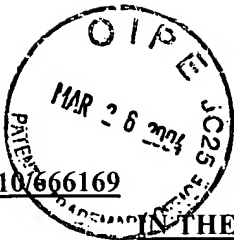
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SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

In compliance with the duty imposed by 37 C.F.R. § 1.56, and in accordance with 37 C.F.R. §§ 1.97 *et. seq.*, the enclosed materials are brought to the attention of the Examiner for consideration in connection with the above-identified patent application. Applicants respectfully request that this Supplemental Information Disclosure Statement be entered and the documents listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to the provisions of MPEP 609, Applicants request that a copy of the 1449 form, initialed as being considered by the Examiner, be returned to the Applicants with the next official communication.

Pursuant to 37 C.F.R. §1.97(b), it is believed that no fee or statement is required with the Supplemental Information Disclosure Statement. However, if an Office Action on the merits has been mailed, the Commissioner is hereby authorized to charge the required fees to Deposit Account No. 19-0743 in order to have this Supplemental Information Disclosure Statement considered.

The Examiner is invited to contact the Applicants' Representative at the below-listed telephone number if there are any questions regarding this communication.

Respectfully submitted,

ABHIJIT JAS ET AL.

By their Representatives,

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Date _19 MARCH 2004_   By _____
                                David R. Cochran
                                Reg. No. 46,632

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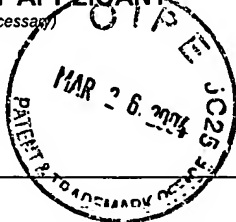
_____Chris Hammond_____   _____Chris Hammond_____
Name   Signature

Substitute for form 1449A/PTO **INFORMATION DISCLOSURE STATEMENT BY APPLICANT** *(Use as many sheets as necessary)*	Complete if Known	
	Application Number	10/666169
	Filing Date	September 19, 2003
	First Named Inventor	Jas, Abhijit
	Group Art Unit	2816
	Examiner Name	Unknown
Sheet 1 of 1	**Attorney Docket No: 884.911US1**	

US PATENT DOCUMENTS

Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	Filing Date If Appropriate
	US-6,032,278	02/29/2000	Parvathala, Praveen , et al.	714	726	12/26/1996
	US-6,477,674	11/05/2002	Bates, Sarah E., et al.	714	738	11/05/2002
	US-6,510,398	01/21/2003	Kundu, Sandip , et al.	702	117	06/22/2000
	US-6,564,347	05/13/2003	Mates, John W.	714	727	07/29/1999

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Foreign Document No	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	T²

OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No [1]	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
		"Linear Feedback Shift Registers", www.math.cudenver.edu/~wcherowi/courses/m5410/m5410fsr.html, 1-8	
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EXAMINER   **DATE CONSIDERED**